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Application
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IDS Flag Clearance for Application [10666470   ]

IDS Information

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M844	09-19-2003	12	☑	08-11-2005 00:48:51 IDS CONV

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EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	2441	716/4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/15 13:47
L2	1889	716/5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/15 13:46
L3	1498	716/6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/15 13:46
L4	0	(716/4).ccls. and (timing adj criticality) and (netlist) and ((boundary adj timing) adj (condition$2 or constraint$2)) and (delay adj variation) and model$4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/15 13:51
L5	0	(716/4).ccls. and (timing adj criticality) and (netlist) and ((boundary adj timing) adj (condition$2 or constraint$2)) and (delay adj variation$2) and model$4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/15 13:51
L6	0	(716/5).ccls. and (timing adj criticality) and (netlist) and ((boundary adj timing) adj (condition$2 or constraint$2)) and (delay adj variation$2) and model$4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/15 13:51
L7	1	(716/6).ccls. and (timing adj criticality) and (netlist) and ((boundary adj timing) adj (condition$2 or constraint$2)) and (delay adj variation$2) and model$4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/15 13:52
L8	1	("716"/$).ccls. and (timing adj criticality) and (netlist) and ((boundary adj timing) adj (condition$2 or constraint$2)) and (delay adj variation$2) and model$4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/15 13:52

| L9 | 1 | (timing adj criticality) and (netlist) and ((boundary adj timing) adj (condition$2 or constraint$2)) and (delay adj variation$2) and model$4 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2006/02/15 13:52 |

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☐   1. **Timing minimization by statistical timing hMetis-based partitioning**
Ababei, C.; Bazargan, K.;
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